

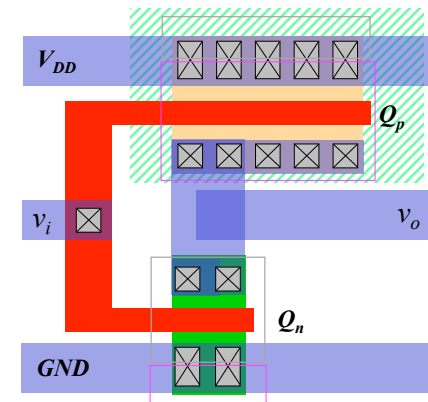
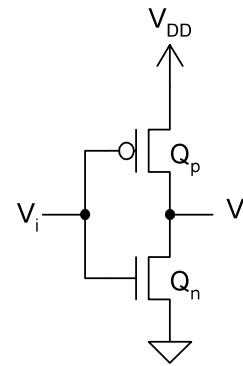
Topic 3

CMOS Fabrication Process

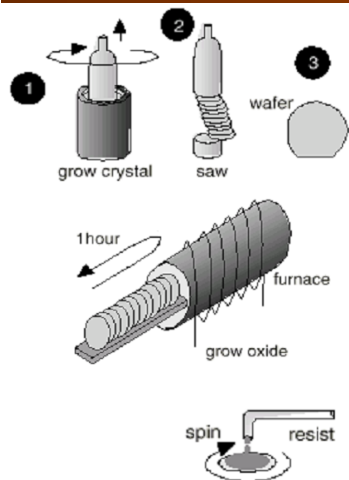
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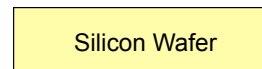
Layout of a Inverter



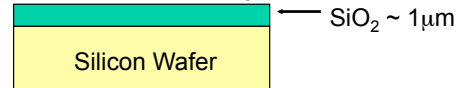
The CMOS Process - photolithography (1)



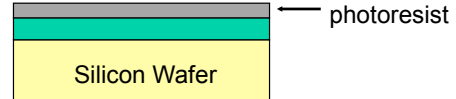
(a) Bare silicon wafer



(b) Grow Oxide layer

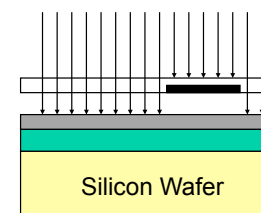


(c) Spin on photoresist

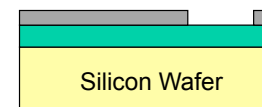


The CMOS Process - photolithography (2)

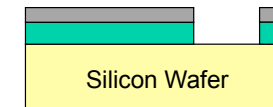
(d) Expose resist to UV light through a MASK



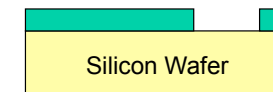
(e) Remove unexposed resist



(f) Etch away oxide

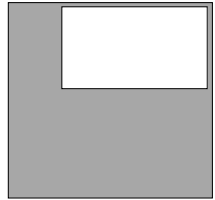


(g) Remove remaining resist

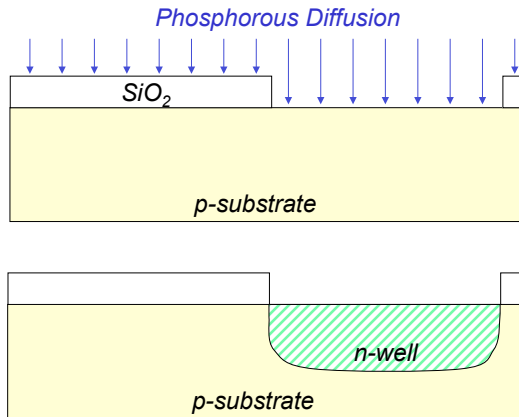


Mask 1: N-well Diffusion

- SiO_2 is etched using Mask 1.

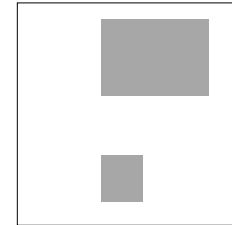


- Phosphorous is diffused into the unmasked regions of silicon creating an n-well for the fabrication of p-channel devices

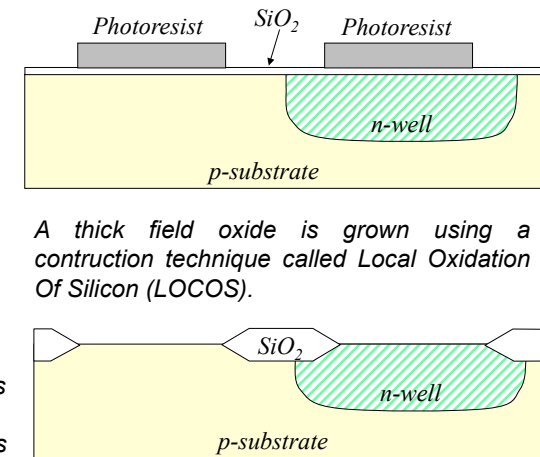


Mask 2: Define Active Regions

- Mask 2 creates the active regions where the MOSFETs will be placed



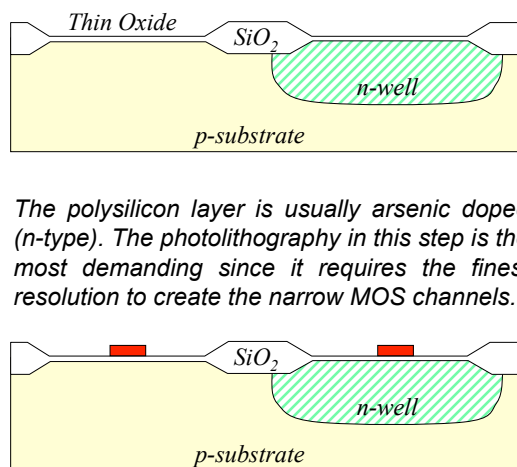
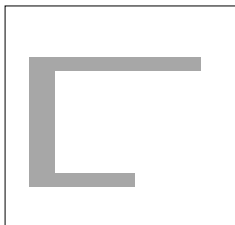
- The thick oxide regions provides isolation between the MOSFETs



A thick field oxide is grown using a contraction technique called Local Oxidation Of Silicon (LOCOS).

Mask 3: Polysilicon Gate

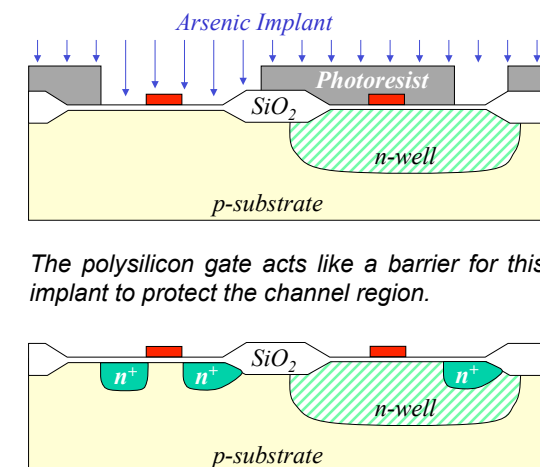
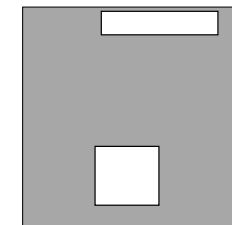
- A high quality thin oxide is grown in the active area ($\sim 100\text{\AA} \rightarrow 300\text{\AA}$)
- Mask 3 is used to deposit the polysilicon gate (most critical step)



The polysilicon layer is usually arsenic doped (n-type). The photolithography in this step is the most demanding since it requires the finest resolution to create the narrow MOS channels.

Mask 4: n+ Diffusion

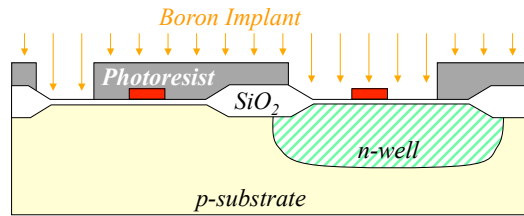
- Mask 4 is used to control a heavy arsenic implant and create the source and drain of the n-channel devices.
- This is a **self-aligned** structure.



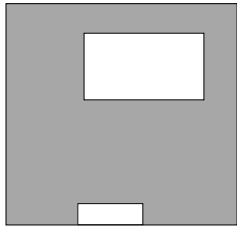
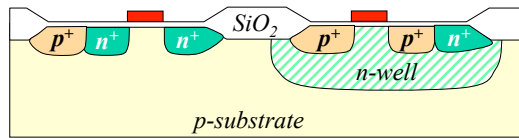
The polysilicon gate acts like a barrier for this implant to protect the channel region.

Mask 5: p+ Diffusion

- Mask 5 is used to control a heavy Boron implant and create the source and drain of the n-channel devices.
- This is a self-aligned structure.

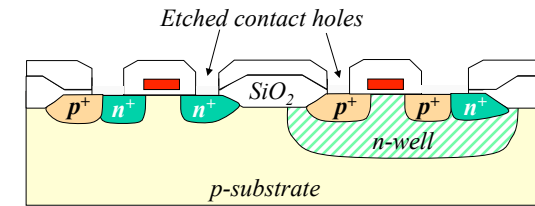
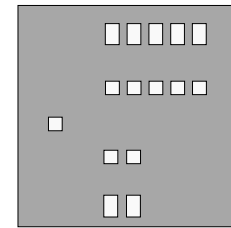
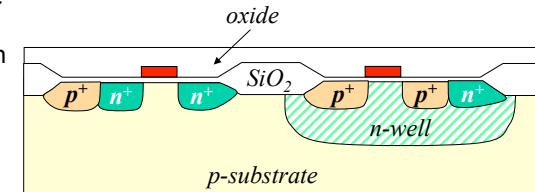


The polysilicon gate acts like a barrier for this implant to protect the channel region.



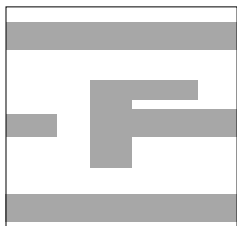
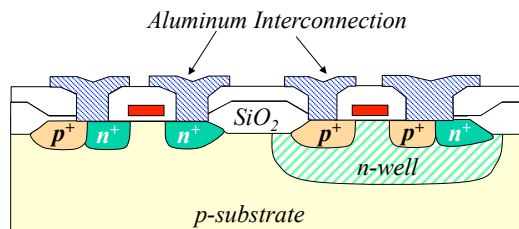
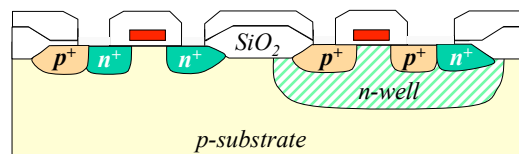
Mask 6: Contact Holes

- A thin layer of oxide is deposited over the entire wafer
- Mask 6 is used to pattern the contact holes
- Etching opens the holes.

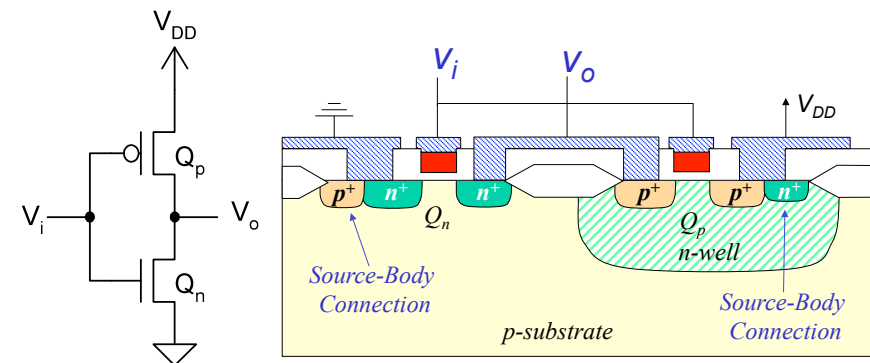


Mask 7: Metalization

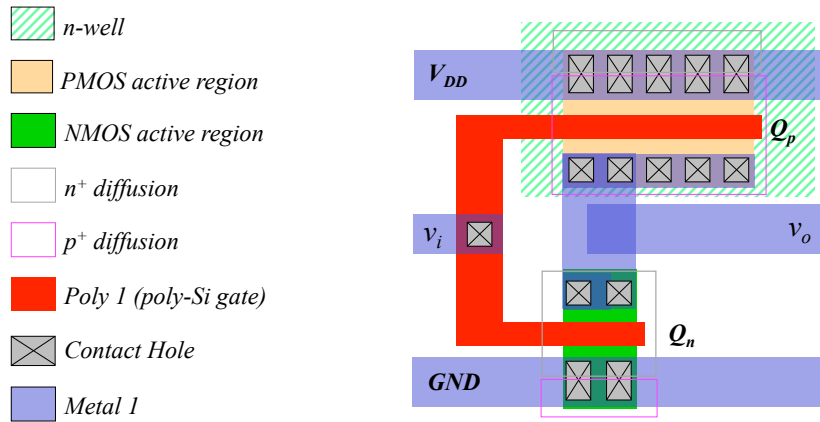
- A thin layer of aluminum is evaporated or sputtered onto the wafer.
- Mask 7 is used to pattern the interconnection.



Cross section of a CMOS Inverter



Physical Layout of an Inverter



Dimension of transistors

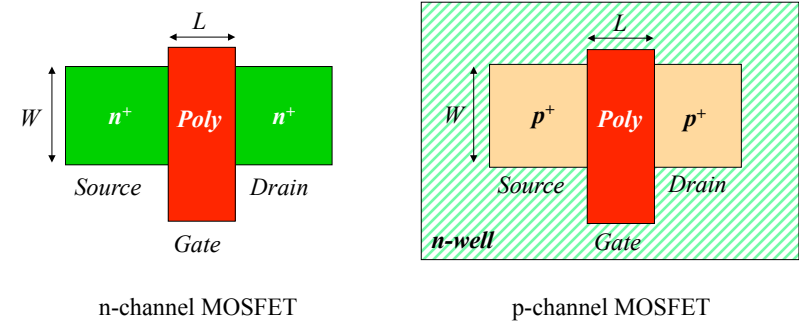
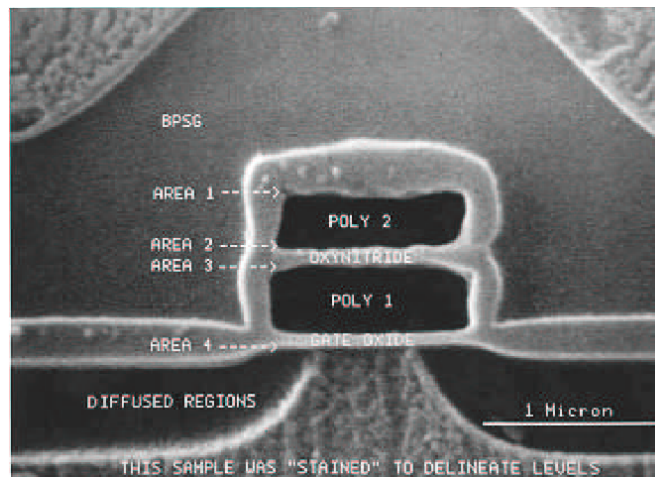
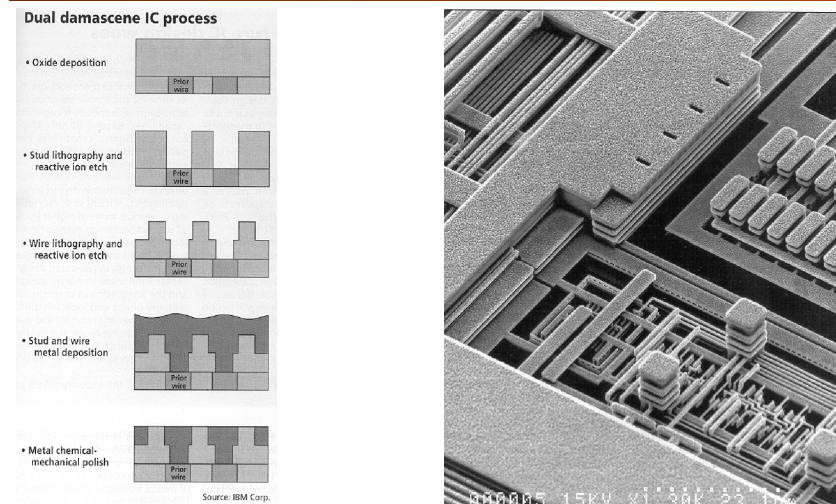


Photo cross-section of a transistor

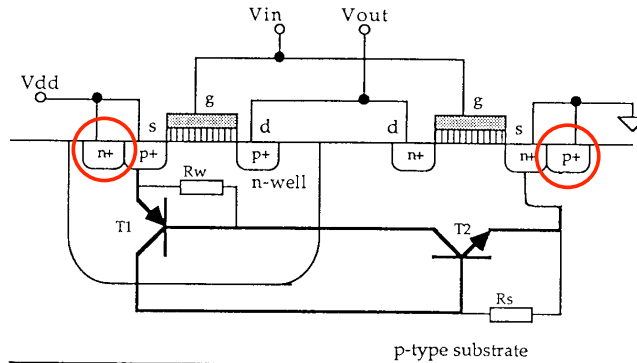


Advanced metalization with polishing



Latch-up problem (1)

- ◆ As shown above, the p+ region of the p-transistor, the n-well and the p- substrate form a parasitic pnp transistor T1.
- ◆ The n- well, the p- substrate and the p+ source of the n-transistor forms another parasitic npn transistor T2.
- ◆ There exists two resistors R_w and R_s due to the resistive drop in the well area and the substrate area.



Latch-up (con't)

- ◆ T1 and T2 form a thyristor circuit.
- ◆ If R_w and/or R_s are not 0, and for some reason (power-up, current spike etc), T1 or T2 are forced to conduct, Vdd will be shorted to Gnd through the small resistances and the transistors.
- ◆ Once the circuit is 'fired', both transistors will remain conducting due to the voltage drop across R_w and R_s . The only way to get out of this mode is to turn the power off.
- ◆ This condition is known as **latch-up**.
- ◆ To avoid latch-up, substrate-taps (tied to Gnd) and well-taps (tied to Vdd) are inserted as frequently as possible. This has the effect of shorting out R_w and R_s .

